

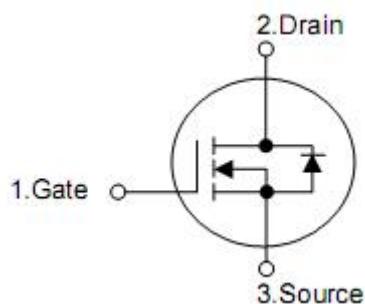
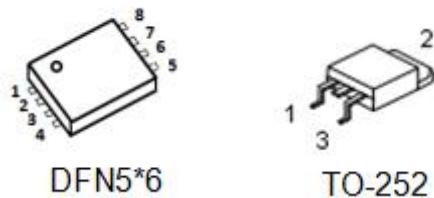
1. Description

The KND3404C is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The KND3404C meet the RoHs and Green Product requirement 100% EAS Guaranteed with full function reliability approved.

2. Features

- $R_{DS(ON),typ.}=5.0\text{m}\Omega @ V_{GS}=10\text{V}$
- Super low gate charge
- 100% EAS Guaranteed
- Green device available
- Excellent Cdv/dt effect decline
- Advanced high cell density trench technology

3. Symbol



Pin TO-252	Pin DFN5*6	Function
1	4	Gate
2	5,6,7,8	Drain
3	1,2,3	Source

4. Ordering Information

Part Number	Package	Brand
KND3404C	TO-252	KIA
KNY3404C	DFN5*6	KIA

5. Absolute maximum ratings

($T_A=25^\circ\text{C}$,unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DS}	40	V
Gate-source voltage	V_{GS}	± 20	V
Continuous drain current $V_{GS}@10\text{V}^1$	I_D	80	A
	I_D	58	A
Pulsed drain current ²	I_{DM}	150	A
Single pulse avalanche energy ³	EAS	110	mJ
Avalanche current	I_{AS}	47	A
Total power dissipation ⁴	P_D	52.1	W
Junction and storage temperature range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

6. Thermal Data

Parameter	Symbol	Ratings	Units
Thermal resistance,junction-ambient	R_{thJA}	62	$^\circ\text{C/W}$
Thermal resistance,Junction-case	R_{thJC}	2.4	$^\circ\text{C/W}$

7.Electrical characteristics

($T_J=25^\circ\text{C}$,unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	40	--	--	V
BVDSS Temperature Coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Reference to 25°C , $I_D=1\text{mA}$	--	0.034	--	$\text{V}/^\circ\text{C}$
Static Drain-Source On-Resistance ²	$R_{\text{DS}(\text{ON})}$	TO-252 $V_{\text{GS}}=10\text{V}$, $I_D=15\text{A}$ DFN5*6 $V_{\text{GS}}=10\text{V}$, $I_D=10\text{A}$	--	5.0	6.5	$\text{m}\Omega$
		TO-252 $V_{\text{GS}}=4.5\text{V}$, $I_D=12\text{A}$ DFN5*6 $V_{\text{GS}}=4.5\text{V}$, $I_D=5\text{A}$		6.5	9	$\text{m}\Omega$
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$	1.0	--	2.5	V
VGS(th) Temperature Coefficient	$\Delta V_{\text{GS}(\text{th})}$	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$	--	-5.84	--	$\text{mV}/^\circ\text{C}$
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=32\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	--	---	1	uA
		$V_{\text{DS}}=32\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=55^\circ\text{C}$	--	---	5	uA
Gate-Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	--	---	± 100	nA
Forward Transconductance	g_{fs}	$V_{\text{DS}}=5\text{V}$, $I_D=15\text{A}$	--	25	---	S
Gate Resistance	R_g	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	--	1.5	---	Ω
Total Gate Charge (4.5V)	Q_g	$V_{\text{DS}}=20\text{V}$, $V_{\text{GS}}=4.5\text{V}$, $I_D=12\text{A}$	--	28	---	nC
Gate-Source Charge	Q_{gs}		--	7.8	---	nC
Gate-Drain Charge	Q_{gd}		--	12.5	---	nC
Turn-On Delay Time	$T_{\text{d}(\text{on})}$	$V_{\text{DD}}=15\text{V}$, $V_{\text{GS}}=10\text{V}$, $R_G=3.3\Omega$, $I_D=1\text{A}$	--	20	---	ns
Rise Time	T_r		--	11.5	---	ns
Turn-Off Delay Time	$T_{\text{d}(\text{off})}$		--	84	---	ns
Fall Time	T_f		--	8.5	---	ns
Input Capacitance	C_{iss}	$V_{\text{DS}}=15\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	--	3330	---	pF
Output Capacitance	C_{oss}		--	270	---	pF
Reverse Transfer Capacitance	C_{rss}		--	200	---	pF
Diode Characteristics						
Continuous Source Current ^{1,5}	I_s	$V_G=V_D=0\text{V}$, Force Current	--	--	80	A
Pulsed Source Current ^{2,5}	I_{SM}		--	--	150	A
Diode Forward Voltage ²	V_{SD}	$V_{\text{GS}}=0\text{V}$, $I_s=1\text{A}$, $T_J=25^\circ\text{C}$	--	--	1	V

Note:1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2. The data tested by pulsed, pulse width $\leq 300\text{us}$,duty cycle $\leq 2\%$.

3. The EAS data shows Max.rating. The test condition is $V_{\text{DD}}=25\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.1\text{mH}$, $I_{\text{AS}}=47\text{A}$.

4. The power dissipation is limited by $150\text{ }^\circ\text{C}$ junction temperature.

5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation

8. Test circuits

Typical Characteristics

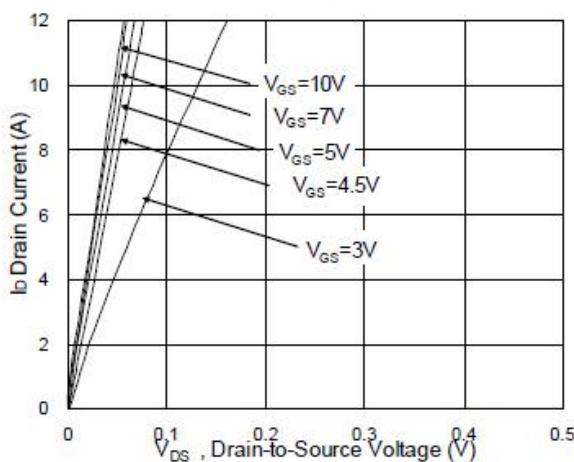


Fig.1 Typical Output Characteristics

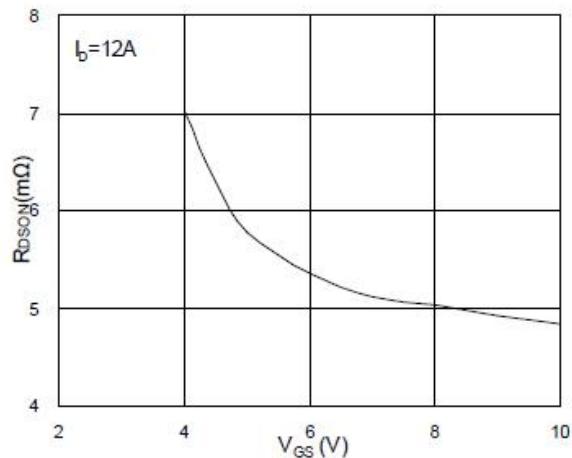


Fig.2 On-Resistance vs. G-S Voltage

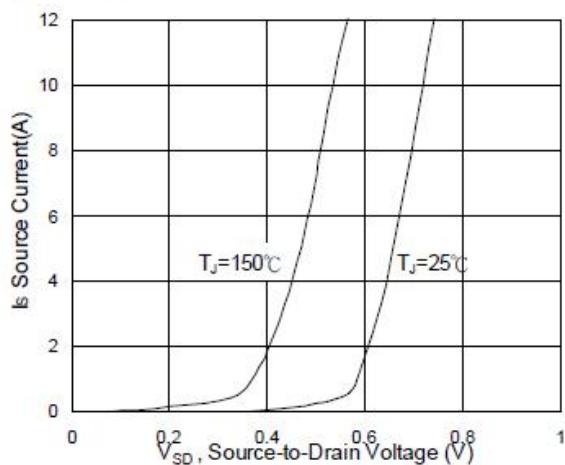


Fig.3 Forward Characteristics Of Reverse

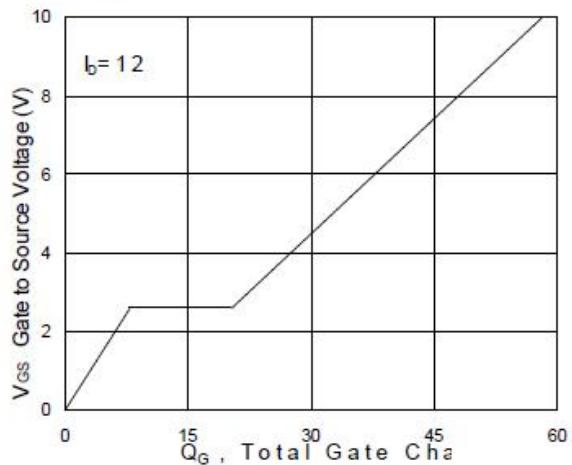


Fig.4 Gate-Charge Characteristics

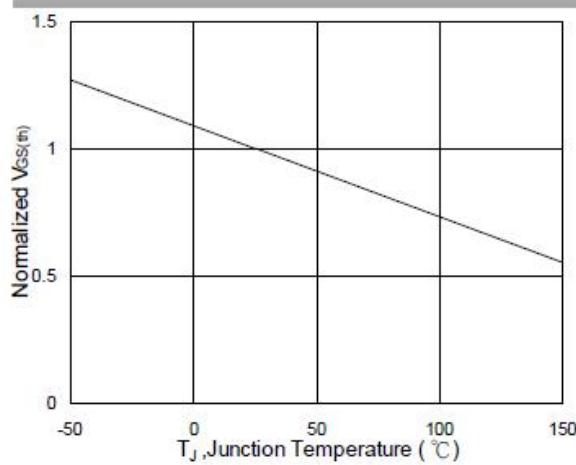


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

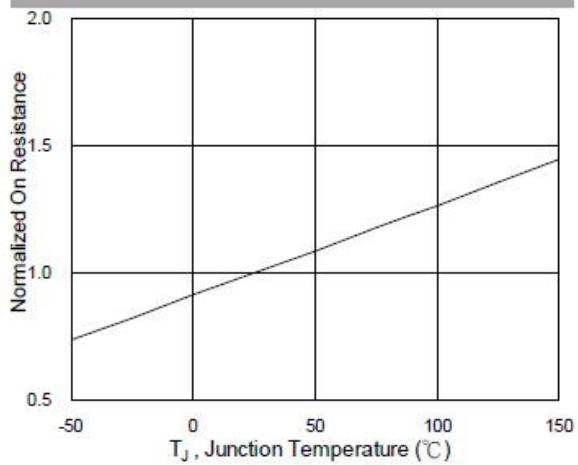


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

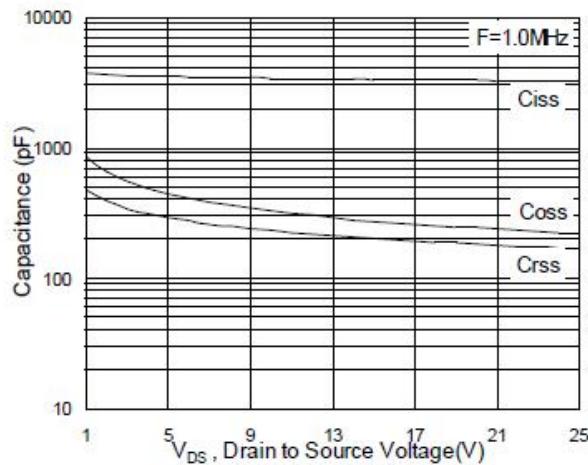


Fig.7 Capacitance

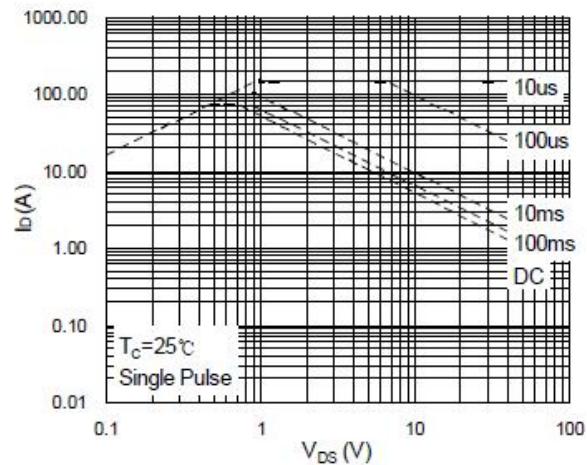


Fig.8 Safe Operating Area

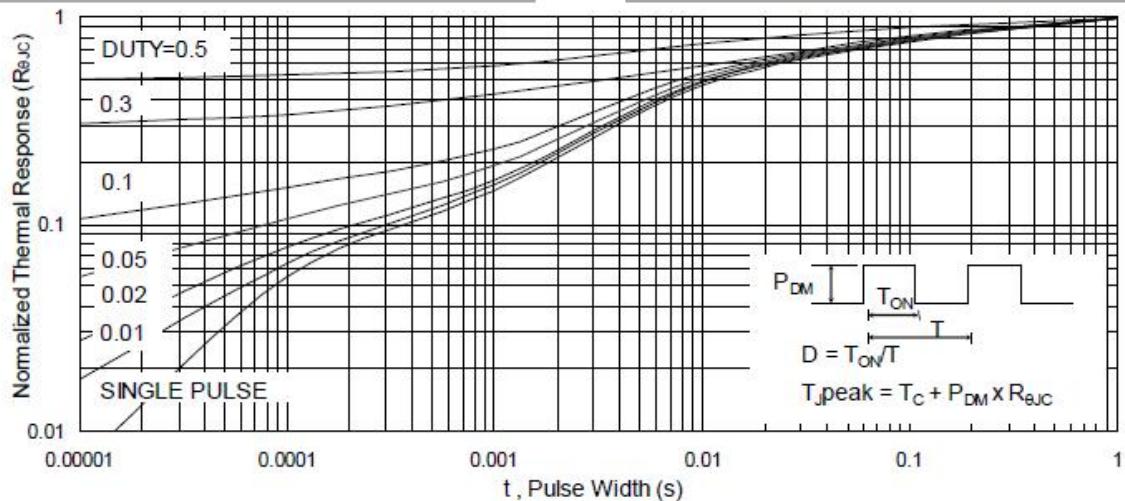


Fig.9 Normalized Maximum Transient Thermal Impedance

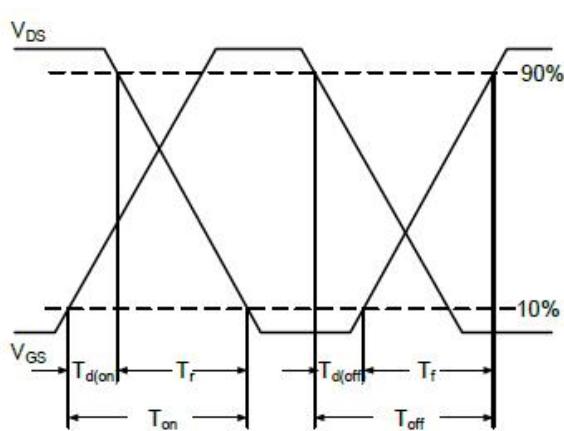


Fig.10 Switching Time Waveform

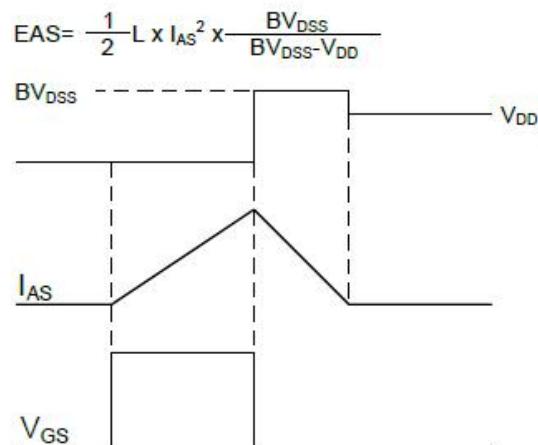


Fig.11 Unclamped Inductive Switching Wave